Hybrid 7p174 Traveler

February 11, 2000

1 Connectivity

Repairs on shorts:

Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 7P174 has die: 175-066 175-067 175-068 175-069 175-070 175-072 175-074

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 7p174 classification info. Created 11:07:33 02/11/00

Hybrid 7p174 quality: fair
Chip classification: fair fair good fair fair fair good
Bad channels (chip-channel): 1-84
Bad cells: none
Random bad capacitors (chip-cell-channel): 0-27-109 3-45-4 3-45-66
   3-6-62 4-30-41 4-36-62 5-43-118
Channels at pedestal needed for DCMS: 35.6 33.6 31.7 36.7 34.7 34.5 36.6
```

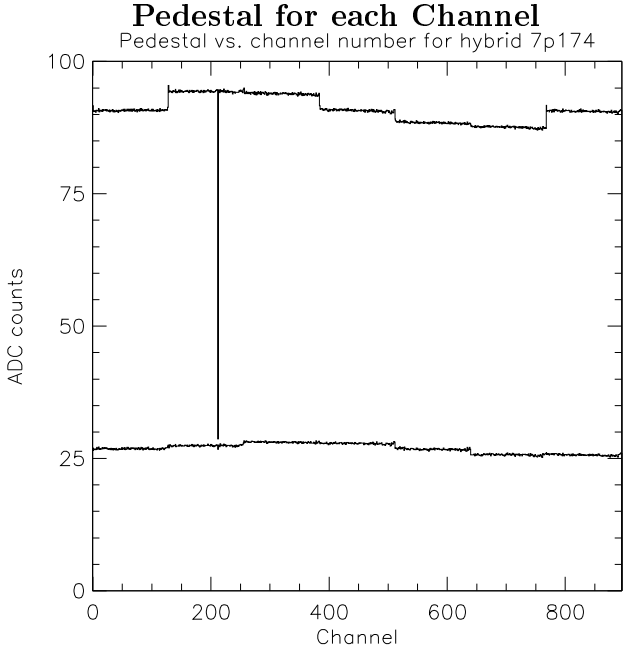
4 Comments

Encapsulated. FE DV finger gold bonds. HV tested.

5 Pedestal

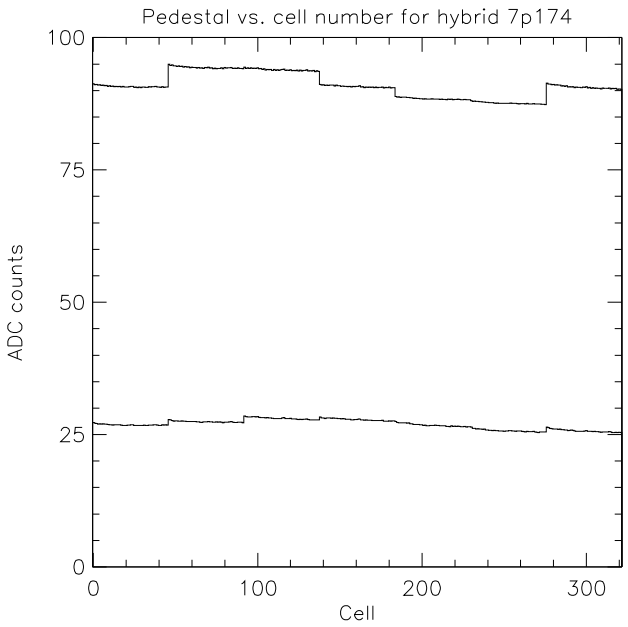
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

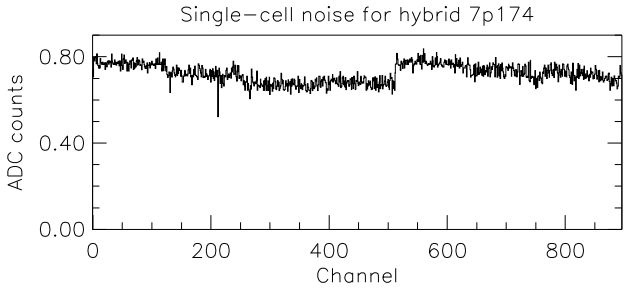
Pedestal vs. Pipeline Cell ID

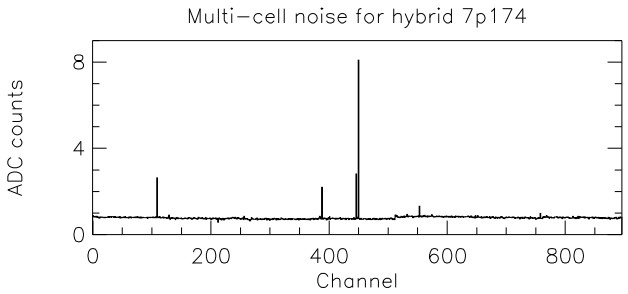


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

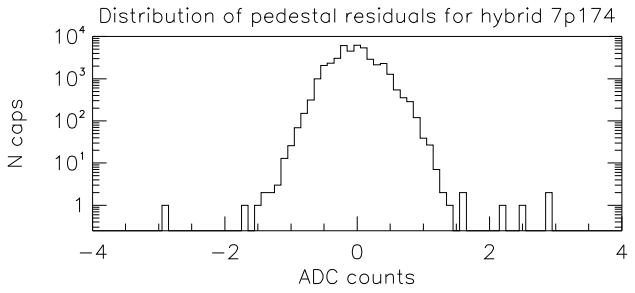
RMS Noise

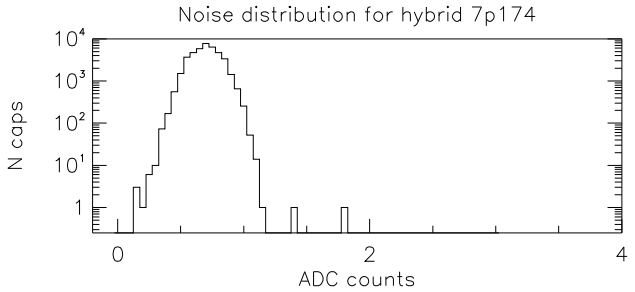




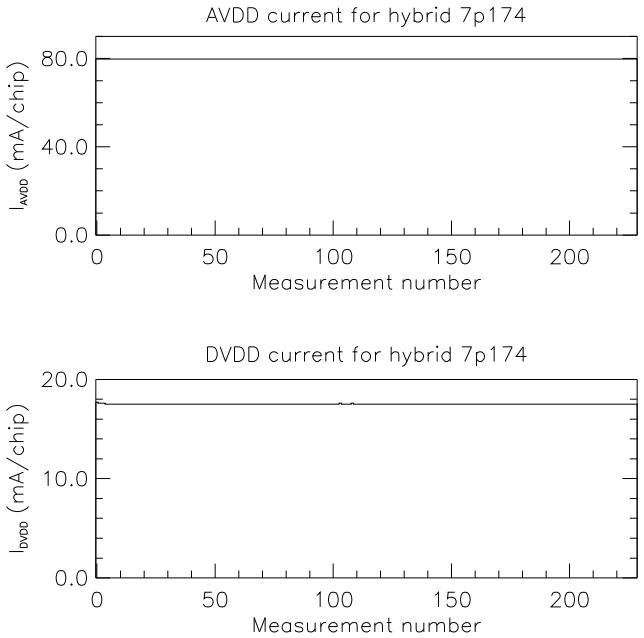
The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in